



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Kon-Sult, Inc.

**6 Birch Street
Hudson, NH 03051**

Fulfills the requirements of

ISO/IEC 17025:2017

and national standard

ANSI/NCSL Z540-1-1994 (R2002)

In the field of

CALIBRATION

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

A handwritten signature in black ink, appearing to be 'Jason Stine', is positioned above a horizontal line.

Jason Stine, Vice President
Expiry Date: 04 October 2026
Certificate Number: AC-1243



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

**SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017
AND
ANSI/NCSL Z540-1-1994 (R2002)**

Kon-Sult, Inc.
6 Birch Street
Hudson, NH 03051
June Kopka 603-882-7464

CALIBRATION

Valid to: **October 4, 2026**

Certificate Number: **AC-1243**

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Angle Blocks/Plates ²	Up to 90°	14"	Electronic Amp, Sine Bar, Surface Plate
1-2-3 Blocks Parallelism Squareness	Up to 3 in Up to 76 mm	20 µin 0.51 µm 61 µin 1.5 µm	Comparison to Gage Blocks, Electronic Amp, Linear Height, Surface Plate
2-4-6 Blocks Parallelism Squareness	Up to 6 in Up to 152 mm	27 µin 0.69 µm 89 µin 2.3 µm	Comparison to Gage Blocks, Electronic Amp, Linear Height, Surface Plate
Angle Irons Parallelism Squareness	Up to 6 in Up to 152 mm	18 µin 0.5 µm 88 µin 2.2 µm	Electronic Amp, Linear Height, Surface Plate
Parallels	Up to 12 in Up to 305 mm	36 µin 0.9 µm	Electronic Amp, Surface Plate
Sine Bars/Plates	5 in 127 mm 10 in 254 mm	24 µin 0.6 µm 35 µin 0.88 µm	Electronic Amp, Gage Blocks, Surface Plate

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Vee Blocks Parallelism Squareness	Up to 5 in Up to 127 mm	31 μin 0.8 μm 77 μin 2 μm	Electronic Amp, Surface Plate
Protractor ^{1,2}	Up to 90°	15"	Angle Blocks
Gage Blocks ²	Up to 8 in	(3 + 5L) μin	Comparison to Master Gage Blocks, Electronic Comparator
Dial/Digital Indicators ¹ Resolution 0.000 05 in 0.000 1 in 0.000 5 in 0.001 in	Up to 4 in Up to 4 in Up to 4 in Up to 4 in	53.2 μin 74 μin 292 μin 580 μin	Gage Blocks
Test Indicator ¹	Up to 0.1 in Up to 0.25 mm	70 μin 1.2 μm	Gage Blocks, Surface Plate
Bore Gages Indicator Resolution 0.000 05 in 0.000 1 in 0.000 5 in 0.001 in	Up to 12 in Up to 12 in Up to 12 in Up to 12 in	56.8 μin 75.6 μin 292 μin 580 μin	Micrometer Head
Electronic Amplifiers 5 μin resolution 0.1 μm resolution	Up to 0.05 in Up to 1.3 mm	6 μin 0.15 μm	Gage Blocks, Surface Plate
Linear Measuring Machines ^{1,2}	Up to 40 in	(63 + 4L) μin	Gage Blocks, Force Gauge
Bench Micrometer ¹	Up to 11 in	25 μin	Gage Blocks, Force Gauge
Micrometers ^{1,2}	Up to 40 in	(78 + 4.2L) μin	Gage Blocks
Depth Micrometers ^{1,2}	Up to 12 in	(175 + 5L) μin	Gage Blocks
Inside Micrometer ^{1,2}	Up to 40 in	(48 + 2L) μin	Gage Blocks
Micrometer Head ¹	Up to 2 in Up to 50 mm	64 μin 1.6 μm	Gage Blocks
Height Master ²	Up to 40 in	(8 + 3L) μin	Gage Blocks, Electronic Amplifier

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Height Gage ^{1,2}	Up to 40 in	$(190 + 11L) \mu\text{in}$	Gage Blocks, Surface Plate
Intrimike ¹	Up to 6 in	71 μin	Master Rings
	Up to 152 mm	1.8 μm	
Calipers / Verniers ^{1,2}	Up to 80 in	$(578 + 8L) \mu\text{in}$	Gage Blocks, Micrometer Standards
Micrometer Standards ²	Up to 38 in	$(34 + 5L) \mu\text{in}$	Gage Blocks, Linear Measuring Machines
Thread Plug Gages Major Diameter	Up to 6 in	54 μin	Bench Micrometer, Gage Blocks, Thread Measuring Wires
	Up to 150 mm	1.4 μm	
Pitch Diameter	Up to 6 in	99 μin	Bench Micrometer, Gage Blocks, Thread Measuring Wires
	Up to 150 mm	2.5 μm	
Plain Plug Gages	Up to 2 in	20 μin	Gage Blocks, Electronic Comparator
	Up to 50 mm	0.36 μm	
Plain Ring Gages	Up to 6 in	32 μin	Gage Blocks, Internal/External Comparator
	Up to 150 mm	0.81 μm	
Thread Ring Gages	Up to 6 in	76 μin	Qualitative Measurement Set with Thread Plug Gages
	Up to 150 mm	1.93 μm	
Pin Gages	Up to 1 in	87 μin	Gage Blocks, Micrometer
	Up to 25 mm	1.5 μm	
Squares ²	Up to 18 in	$(20 + 2L) \mu\text{in}$	Linear Height, Surface Plate
Levels	Up to 18 in	64 μin	Gage Blocks, Surface Plate
	Up to 457 mm	1.6 μm	
Granite Surface Plates ^{1,2}	Up to 161 inDL	$(10 + 1.1DL) \mu\text{in}$	In accordance with ASME B89.3.7 using Electronic Levels
Local Area Flatness	Up to 0.002 in	39 μin	Repeat-o-Meter
Feeler Gages ¹	(0.001 to 0.06) in	72 μin	Gage Blocks, Micrometer

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Durometer Type A and Type D	Up to 100 Duro	0.62 Duro	Partial verification per ASTM D2240 using Duro calibrator
Torque Tools	(16 to 160) ozf·in (10 to 100) lbf·in (10 to 100) lbf·ft (100 to 1 000) lbf·ft	2.4 ozf·in 2.6 lbf·in 2.6 lbf·ft 4 lbf·ft	Torque Transducers

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
2. L is the numerical value of the nominal length of the device being measured in inches.; DL is the diagonal length in inches; " = arc-second.
3. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-1243.



Jason Stine, Vice President